

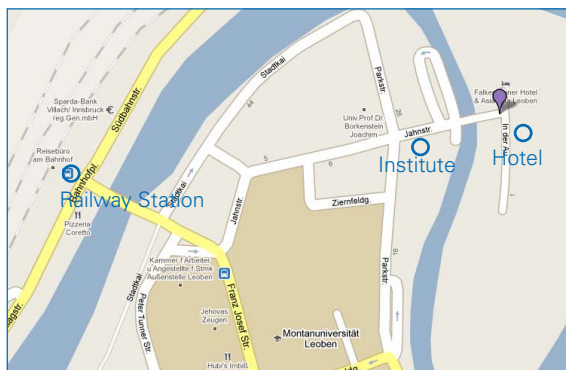


Motivation

In nano-science and nano-technology, there is a need to apply fast characterization approaches in order to reveal the structure of small objects in the nm range. Small-angle X-ray scattering is a well established analytical technique to characterize particle size, distribution and shape in various kinds of biological, pharmaceutical, polymer, fiber samples and nanomaterials. Structural details of nano-structured surfaces can be elaborated by means of the novel GISAXS technique. This method provides complementary information to electron microscopy or AFM. Due to progress in X-Ray laboratory instruments and evaluation techniques, SAXS and GISAXS are rapidly increasing and used for more and more applications.

This workshop provides an overview about the latest scientific achievements and instrumentation development in SAXS and GISAXS. Topics dealing with classical SAXS, in situ time-resolved experiments and advanced surface characterization techniques will be covered by invited speakers. Moreover, a practical training on SAXS and GISAXS techniques and data evaluation will be provided. The workshop is addressed to beginners as well as experts in materials research.

Reaching the Hotel and Institute



Hotel Reservation

We have pre-booked rooms at:
Hotel & Asia Spa Leoben
In der Au 1-3
A-8700 Leoben
T: +43 3842 40 50
F: +43 3842 40 5405
e-mail: leoben@falkensteiner.com
Please make your reservation directly with the hotel and refer to Bruker AXS.
Deadline for hotel reservation is July 31, 2010

Registration

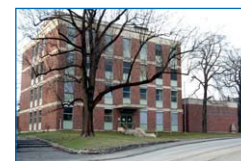
Please reply the completed registration form to:
Materials Center Leoben Forschung GmbH
Roseggerstrasse 12
A-8700 Leoben
T: +43 3842 45922 11
F: +43 3842 459225
e-mail: SAXS2010@mcl.at
www.mcl.at
Deadline for registration is July 31, 2010.

Registration fee

The registration fee is € 480.-.
Registration fee includes lunch, coffee breaks, evening event and receptions.
Accommodation is not included.

Location

Erich Schmid Institut
Jahnstr. 12
8700 Leoben, Austria



Invitation to the 4th International SAXS / GISAXS Workshop

2nd Announcement

**Advanced Small Angle X-ray
Scattering in Biology, Chemistry,
Polymer and Materials Science**

Sep. 9th 13:00 - Sep. 11th 13:00, 2010

Organized by:



**Bruker AXS GmbH
Germany**



**Materials Center
Leoben, Austria**



**Erich Schmid
Institut, Austria**

think forward

SAXS

Agenda:

Thursday 9th, 2010, Afternoon

- 13:00 - 13:10 Opening
13:10 - 13:30 Introduction to the Erich Schmid Institute
R. Pippan, ESI Leoben
13:30 - 14:20 Solution Small-angle X-ray Scattering
J.S. Pedersen, University of Aarhus
14:20 - 15:10 Microfluidic tools for small angle X-ray scattering and diffraction
T. Pfohl, University Basel
15:40 - 16:30 Self Assembled Structures of Block-Copolymer Systems Investigated by SAXS
G. Popovsky, University Leoben
16:30 - 18:00 Workshop, practical training on SAXS

Friday 10th, 2010, Morning

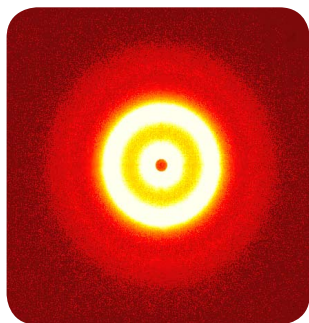
- 9:00 - 9:50 3-D SAXS on Biominerals
B. Aichmayer, MPI Potsdam
9:50 - 10:30 Scanning SAXS/WAXD applications on structured materials
J. Keckes, University Leoben
11:00 - 11:45 SAXS as a powerful tool in materials physics and materials chemistry
H. Peterlik, University of Vienna
11:45 - 12:30 Nanometer sized layered structures – GISAXS studies
E. Majkova, Slovak Academy of Sciences
12:30 - 14:00 Lunch

Friday 10th, 2010, Afternoon

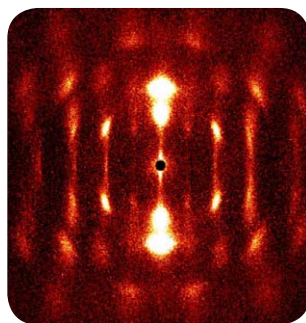
- 14:00 - 14:50 Quantitative surface characterization by Atomic-Force Microscopy
C. Teichert, University Leoben
14:50 - 15:40 Two- and three-dimensional nanoparticle assemblies – GISAXS from liquid to solid surfaces
P. Siffalovic, Slovak Academy of Sciences
16:10 - 16:50 Surface characterization by means of Laboratory GISAXS and 2D-XRR
G. Maier, MCL Leoben
16:50 - 18:00 Workshop, practical training on GISAXS
19:30 Dinner

Saturday 11th, 2010

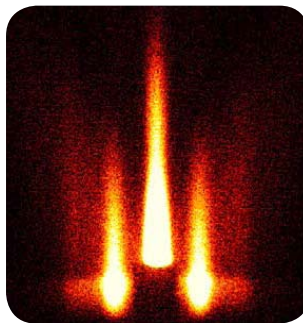
- 9:00 - 9:40 Potential of the Gallium Metal-Jet X-ray Source for SAXS and X-ray Imaging
L. Brügemann, Bruker AXS Karlsruhe
9:40 - 10:20 SAXS studies on Nanoporous Materials
O. Paris, University Leoben
10:50 - 11:30 Analysis of small-angle X-ray scattering data
J.S. Pedersen, University of Aarhus
11:30 - 13:00 Workshop, data interpretation
13:00 Closing



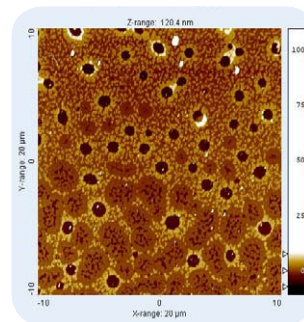
SAXS pattern obtained from a polymer sample



SAXS pattern of a Flax fiber



GISAXS pattern of a nanostructured surface



AFM frame of a FeO sample

SAXS

Registration Form

4th International Workshop on Advanced Small Angle X-ray Scattering in Biology, Chemistry, Polymer and Materials Sciences

Sep. 9th 13:00 - Sep. 11th 13:00, 2010

Yes, I/we will attend!
1st participant

Name, First Name	
Position, Department	
Phone	E-mail
Company	
Street/Post Box	
Post Code/City	
Country	
Contact Person	
Date, Signature	

2nd participant

Name, First Name	
Position, Department	
Phone	E-mail

Fax to +43 3842 459225

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Detach here!

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